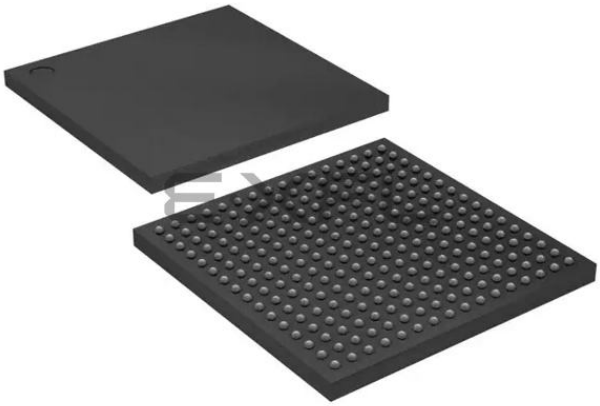

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

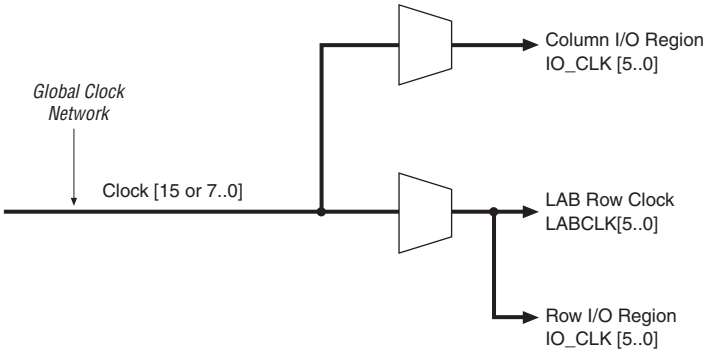
The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	288
Number of Logic Elements/Cells	4608
Total RAM Bits	119808
Number of I/O	158
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	256-LBGA
Supplier Device Package	256-FBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2c5f256c8

Global Clock Network Distribution

Cyclone II devices contains 16 global clock networks. The device uses multiplexers with these clocks to form six-bit buses to drive column IOE clocks, LAB row clocks, or row IOE clocks (see Figure 2–14). Another multiplexer at the LAB level selects two of the six LAB row clocks to feed the LE registers within the LAB.

Figure 2–14. Global Clock Network Multiplexers



LAB row clocks can feed LEs, M4K memory blocks, and embedded multipliers. The LAB row clocks also extend to the row I/O clock regions.

IOE clocks are associated with row or column block regions. Only six global clock resources feed to these row and column regions. Figure 2–15 shows the I/O clock regions.

Each M4K block can implement various types of memory with or without parity, including true dual-port, simple dual-port, and single-port RAM, ROM, and first-in first-out (FIFO) buffers. The M4K blocks support the following features:

- 4,608 RAM bits
- 250-MHz performance
- True dual-port memory
- Simple dual-port memory
- Single-port memory
- Byte enable
- Parity bits
- Shift register
- FIFO buffer
- ROM
- Various clock modes
- Address clock enable

Violating the setup or hold time on the memory block address registers could corrupt memory contents. This applies to both read and write operations.

Table 2–5 shows the capacity and distribution of the M4K memory blocks in each Cyclone II device.

Table 2–5. M4K Memory Capacity & Distribution in Cyclone II Devices

Device	M4K Columns	M4K Blocks	Total RAM Bits
EP2C5	2	26	119,808
EP2C8	2	36	165,888
EP2C15	2	52	239,616
EP2C20	2	52	239,616
EP2C35	3	105	483,840
EP2C50	3	129	594,432
EP2C70	5	250	1,152,000

Table 2–6 summarizes the features supported by the M4K memory.

Table 2–6. M4K Memory Features

Feature	Description
Maximum performance *(1)*	250 MHz
Total RAM bits per M4K block (including parity bits)	4,608
Configurations supported	4K × 1 2K × 2 1K × 4 512 × 8 512 × 9 256 × 16 256 × 18 128 × 32 (not available in true dual-port mode) 128 × 36 (not available in true dual-port mode)
Parity bits	One parity bit for each byte. The parity bit, along with internal user logic, can implement parity checking for error detection to ensure data integrity.
Byte enable	M4K blocks support byte writes when the write port has a data width of 1, 2, 4, 8, 9, 16, 18, 32, or 36 bits. The byte enables allow the input data to be masked so the device can write to specific bytes. The unwritten bytes retain the previous written value.
Packed mode	Two single-port memory blocks can be packed into a single M4K block if each of the two independent block sizes are equal to or less than half of the M4K block size, and each of the single-port memory blocks is configured in single-clock mode.
Address clock enable	M4K blocks support address clock enable, which is used to hold the previous address value for as long as the signal is enabled. This feature is useful in handling misses in cache applications.
Memory initialization file (**.mif**)	When configured as RAM or ROM, you can use an initialization file to pre-load the memory contents.
Power-up condition	Outputs cleared
Register clears	Output registers only
Same-port read-during-write	New data available at positive clock edge
Mixed-port read-during-write	Old data available at positive clock edge

Note to Table 2–6:
(1) Maximum performance information is preliminary until device characterization.

Table 5–11 specifies the bus hold parameters for general I/O pins.

Table 5–11. Bus Hold Parameters *Note (1)*

Parameter	Conditions	V_{CCIO} Level						Unit
		1.8 V		2.5 V		3.3 V		
		Min	Max	Min	Max	Min	Max	
Bus-hold low, sustaining current	$V_{IN} > V_{IL}$(maximum)	30	—	50	—	70	—	µA
Bus-hold high, sustaining current	$V_{IN} < V_{IL}$(minimum)	–30	—	–50	—	–70	—	µA
Bus-hold low, overdrive current	$0 V < V_{IN} < V_{CCIO}$	—	200	—	300	—	500	µA
Bus-hold high, overdrive current	$0 V < V_{IN} < V_{CCIO}$	—	–200	—	–300	—	–500	µA
Bus-hold trip point *(2)*	—	0.68	1.07	0.7	1.7	0.8	2.0	V

Notes to Table 5–11:
(1) There is no specification for bus-hold at V_{CCIO} = 1.5 V for the HSTL I/O standard.
(2) The bus-hold trip points are based on calculated input voltages from the JEDEC standard.

On-Chip Termination Specifications

Table 5–12 defines the specifications for internal termination resistance tolerance when using series or differential on-chip termination.

Table 5–12. Series On-Chip Termination Specifications

Symbol	Description	Conditions	Resistance Tolerance			
			Commercial Max	Industrial Max	Extended/ Automotive Temp Max	Unit
25-Ω R_S	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 3.3V	±30	±30	±40	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 2.5V	±30	±30	±40	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.8V	±30 *(1)*	±40	±50	%

Note to Table 5–12:
(1) For commercial –8 devices, the tolerance is ±40%.

Table 5–21. EP2C5/A Column Pins Global Clock Timing Parameters (Part 2 of 2)

Parameter	Fast Corner		–6 Speed Grade	–7 Speed Grade (1)	–7 Speed Grade (2)	–8 Speed Grade	Unit
	Industrial/ Automotive	Commercial					
$t_{PLLCOUT}$	–0.174	–0.186	0.11	0.07	0.071	0.081	ns

Notes to Table 5–21:
(1) These numbers are for commercial devices.
(2) These numbers are for automotive devices.

Table 5–22. EP2C5/A Row Pins Global Clock Timing Parameters

Parameter	Fast Corner		–6 Speed Grade	–7 Speed Grade (1)	–7 Speed Grade (2)	–8 Speed Grade	Unit
	Industrial/ Automotive	Commercial					
t_{CIN}	1.212	1.267	2.210	2.351	2.54	2.540	ns
t_{COUT}	1.214	1.269	2.226	2.364	2.548	2.548	ns
t_{PLLCIN}	–0.259	–0.277	–0.043	–0.095	–0.106	–0.096	ns
$t_{PLLCOUT}$	–0.257	–0.275	–0.027	–0.082	–0.098	–0.088	ns

Notes to Table 5–22:
(1) These numbers are for commercial devices.
(2) These numbers are for automotive devices.

EP2C8/A Clock Timing Parameters

Tables 5–23 and 5–24 show the clock timing parameters for EP2C8/A devices.

Table 5–23. EP2C8/A Column Pins Global Clock Timing Parameters (Part 1 of 2)

Parameter	Fast Corner		–6 Speed Grade	–7 Speed Grade (1)	–7 Speed Grade (2)	–8 Speed Grade	Unit
	Industrial/ Automotive	Commercial					
t_{CIN}	1.339	1.404	2.405	2.565	2.764	2.774	ns
t_{COUT}	1.353	1.419	2.439	2.597	2.793	2.803	ns
t_{PLLCIN}	–0.193	–0.204	0.055	0.015	0.016	0.026	ns

Table 5–38. Default Loading of Different I/O Standards for Cyclone II Device (Part 2 of 2)

I/O Standard	Capacitive Load	Unit
SSTL_18_CLASS_II	0	pF
1.5V_HSTL_CLASS_I	0	pF
1.5V_HSTL_CLASS_II	0	pF
1.8V_HSTL_CLASS_I	0	pF
1.8V_HSTL_CLASS_II	0	pF
DIFFERENTIAL_SSTL_2_CLASS_I	0	pF
DIFFERENTIAL_SSTL_2_CLASS_II	0	pF
DIFFERENTIAL_SSTL_18_CLASS_I	0	pF
DIFFERENTIAL_SSTL_18_CLASS_II	0	pF
1.5V_DIFFERENTIAL_HSTL_CLASS_I	0	pF
1.5V_DIFFERENTIAL_HSTL_CLASS_II	0	pF
1.8V_DIFFERENTIAL_HSTL_CLASS_I	0	pF
1.8V_DIFFERENTIAL_HSTL_CLASS_II	0	pF
LVDS	0	pF
1.2V_HSTL	0	pF
1.2V_DIFFERENTIAL_HSTL	0	pF

Table 5–56. Maximum DCD for SDR Output on Column I/O Notes (1), (2) *(Part 2 of 2)*

Column I/O Output Standard	C6	C7	C8	Unit
2.5-V	140	140	155	ps
1.8-V	115	115	165	ps
1.5-V	745	745	770	ps
SSTL-2 Class I	60	60	75	ps
SSTL-2 Class II	60	60	80	ps
SSTL-18 Class I	60	130	130	ps
SSTL-18 Class II	60	135	135	ps
HSTL-18 Class I	60	115	115	ps
HSTL-18 Class II	75	75	100	ps
HSTL-15 Class I	150	150	150	ps
HSTL-15 Class II	135	135	155	ps
Differential SSTL-2 Class I	60	60	75	ps
Differential SSTL-2 Class II	60	60	80	ps
Differential SSTL-18 Class I	60	130	130	ps
Differential SSTL-18 Class II	60	135	135	ps
Differential HSTL-18 Class I	60	115	115	ps
Differential HSTL-18 Class II	75	75	100	ps
Differential HSTL-15 Class I	150	150	150	ps
Differential HSTL-15 Class II	135	135	155	ps
LVDS	60	60	60	ps
Simple RSDS	60	70	70	ps
Mini-LVDS	60	60	60	ps

Notes to Table 5–56:

(1) The DCD specification is characterized using the maximum drive strength available for each I/O standard.

(2) Numbers are applicable for commercial, industrial, and automotive devices.

Table 5–57. Maximum for DDIO Output on Row Pins with PLL in the Clock Path Notes (1), (2) *(Part 1 of 2)*

Row Pins with PLL in the Clock Path	C6	C7	C8	Unit
LVCMOS	270	310	310	ps
LVTTL	285	305	335	ps
2.5-V	180	180	220	ps
1.8-V	165	175	205	ps

The actual half period is then = 3000 ps – 155 ps = 2845 ps

Table 5–58. Maximum DCD for DDIO Output on Column I/O Pins with PLL in the Clock Path *Notes (1), (2)*

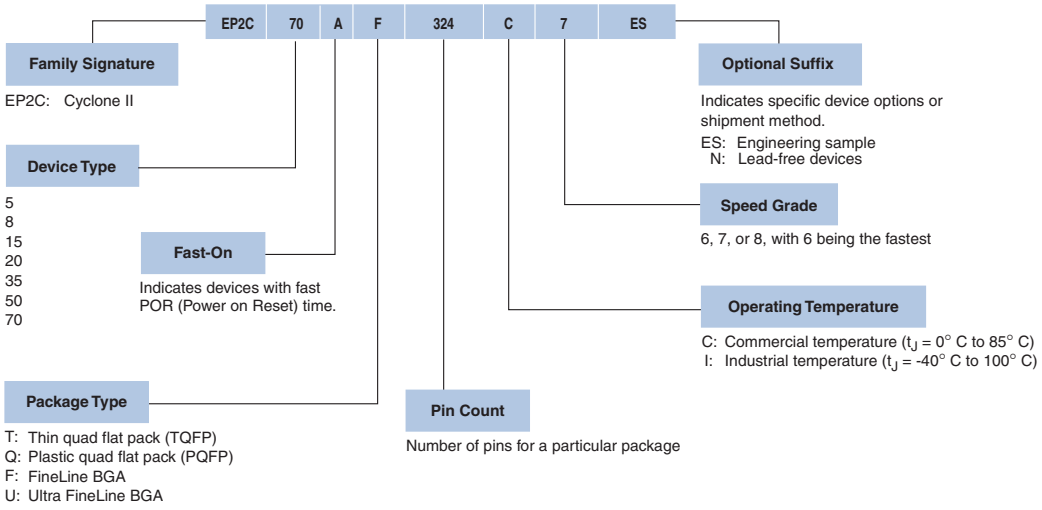
Column I/O Pins in the Clock Path	C6	C7	C8	Unit
LVCMOS	285	400	445	ps
LVTTL	305	405	460	ps
2.5-V	175	195	285	ps
1.8-V	190	205	260	ps
1.5-V	605	645	645	ps
SSTL-2 Class I	125	210	245	ps
SSTL-2 Class II	195	195	195	ps
SSTL-18 Class I	130	240	245	ps
SSTL-18 Class II	135	270	330	ps
HSTL-18 Class I	135	240	240	ps
HSTL-18 Class II	165	240	285	ps
HSTL-15 Class I	220	335	335	ps
HSTL-15 Class II	190	210	375	ps
Differential SSTL-2 Class I	125	210	245	ps
Differential SSTL-2 Class II	195	195	195	ps
Differential SSTL-18 Class I	130	240	245	ps
Differential SSTL-18 Class II	132	270	330	ps
Differential HSTL-18 Class I	135	240	240	ps
Differential HSTL-18 Class II	165	240	285	ps
Differential HSTL-15 Class I	220	335	335	ps
Differential HSTL-15 Class II	190	210	375	ps
LVDS	110	120	125	ps
Simple RSDS	125	125	275	ps
Mini-LVDS	110	120	125	ps

Notes to Table 5–58:

(1) The DCD specification is characterized using the maximum drive strength available for each I/O standard.

(2) Numbers are applicable for commercial, industrial, and automotive devices.

Figure 6–1. Cyclone II Device Packaging Ordering Information



Document Revision History

Table 6–1 shows the revision history for this document.

Table 6–1. Document Revision History

Date & Document Version	Changes Made	Summary of Changes
February 2007 v1.5	• Added document revision history. • Updated Figure 6–1.	• Added Ultra FineLine BGA detail in UBGA Package information in Figure 6–1.
November 2005 v1.2	Updated software introduction.	
November 2004 v1.1	Updated Figure 6–1.	
June 2004 v1.0	Added document to the Cyclone II Device Handbook.	

7. PLLs in Cyclone II Devices

CII51007-3.1

Introduction

Cyclone® II devices have up to four phase-locked loops (PLLs) that provide robust clock management and synthesis for device clock management, external system clock management, and I/O interfaces. Cyclone II PLLs are versatile and can be used as a zero delay buffer, a jitter attenuator, a low skew fan out buffer, or a frequency synthesizer.

Each Cyclone II device has up to four PLLs, supporting advanced capabilities such as clock switchover and programmable switchover. These PLLs offer clock multiplication and division, phase shifting, and programmable duty cycle and can be used to minimize clock delay and clock skew, and to reduce or adjust clock-to-out (t_{CO}) and set-up (t_{SU}) times.

Cyclone II devices also support a power-down mode where unused clock networks can be turned off. The Altera® Quartus® II software enables the PLLs and their features without requiring any external devices.

Cyclone II PLLs have been characterized to operate in the commercial junction temperature range (0° to 85° C), the industrial junction temperature range (-40° to 100° C) and the extended temperature range (-40° to 125° C).

Table 7–1 shows the PLLs available in each Cyclone II device.

Table 7–1. Cyclone II Device PLL Availability

Device	PLL1	PLL2	PLL3	PLL4
EP2C5	✓	✓		
EP2C8	✓	✓		
EP2C15	✓	✓	✓	✓
EP2C20	✓	✓	✓	✓
EP2C35	✓	✓	✓	✓
EP2C50	✓	✓	✓	✓
EP2C70	✓	✓	✓	✓

Table 10–1. Cyclone II Supported I/O Standards and Constraints (Part 2 of 2)

I/O Standard	Type	V_{CCIO} Level		Top and Bottom I/O Pins		Side I/O Pins		
		Input	Output	CLK, DQS	User I/O Pins	CLK, DQS	PLL_OUT	User I/O Pins
Differential HSTL-15 class I or class II	Pseudo differential *(3)*	*(4)*	1.5 V	—	—	—	✓ *(6)*	—
		1.5 V	*(4)*	✓ *(5)*	—	✓ *(5)*	—	—
Differential HSTL-18 class I or class II	Pseudo differential *(3)*	*(4)*	1.8 V	—	—	—	✓ *(6)*	—
		1.8 V	*(4)*	✓ *(5)*	—	✓ *(5)*	—	—
LVDS	Differential	2.5 V	2.5 V	✓	✓	✓	✓	✓
RSDS and mini-LVDS *(7)*	Differential	*(4)*	2.5 V	—	✓	—	✓	✓
LVPECL *(8)*	Differential	3.3 V/ 2.5 V/ 1.8 V/ 1.5 V	*(4)*	✓	—	✓	—	—

Notes to Table 10–1:

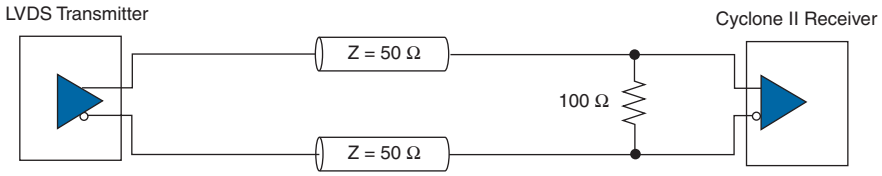
(1) These pins support SSTL-18 class II and 1.8- and 1.5-V HSTL class II inputs.
(2) PCI-X does not meet the IV curve requirement at the linear region. PCI-clamp diode is not available on top and bottom I/O pins.
(3) Pseudo-differential HSTL and SSTL outputs use two single-ended outputs with the second output programmed as inverted. Pseudo-differential HSTL and SSTL inputs treat differential inputs as two single-ended HSTL and SSTL inputs and only decode one of them.
(4) This I/O standard is not supported on these I/O pins.
(5) This I/O standard is only supported on the dedicated clock pins.
(6) `PLL_OUT` does not support differential SSTL-18 class II and differential 1.8 and 1.5-V HSTL class II.
(7) mini-LVDS and RSDS are only supported on output pins.
(8) LVPECL is only supported on clock inputs, not DQS and dual-purpose clock pins.

3.3-V LVTTL (EIA/JEDEC Standard JESD8-B)

The 3.3-V LVTTL I/O standard is a general-purpose, single-ended standard used for 3.3-V applications. The LVTTL standard defines the DC interface parameters for digital circuits operating from a 3.0-/3.3-V power supply and driving or being driven by LVTTL-compatible devices.

The LVTTL input standard specifies a wider input voltage range of $-0.3\ V \leq V_I \leq 3.9\ V$. Altera recommends an input voltage range of $-0.5\ V \leq V_I \leq 4.1\ V$.

Figure 11–11. LVPECL I/O Interface



Differential SSTL Support in Cyclone II Devices

The differential SSTL I/O standard is a memory bus standard used for applications such as high-speed double data rate (DDR) SDRAM interfaces. The differential SSTL I/O standard is similar to voltage referenced SSTL and requires two differential inputs with an external termination voltage (V_{TT}) of 0.5 × V_{CCIO} to which termination resistors are connected. A 2.5-V output source voltage is required for differential SSTL-2, while a 1.8-V output source voltage is required for differential SSTL-18. The differential SSTL output standard is only supported at PLLCLKOUT pins using two single-ended SSTL output buffers programmed to have opposite polarity.

The differential SSTL input standard is supported at the global clock (GCLK) pins only, treating differential inputs as two single-ended SSTL, and only decoding one of them.

For SSTL signaling characteristics, see the *DC Characteristics & Timing Specification* chapter and the *Selectable I/O Standards in Cyclone II Devices* chapter in Volume 1 of the *Cyclone II Device Handbook*.

Figures 11–12 and 11–13 show the differential SSTL class I and II interfaces, respectively.

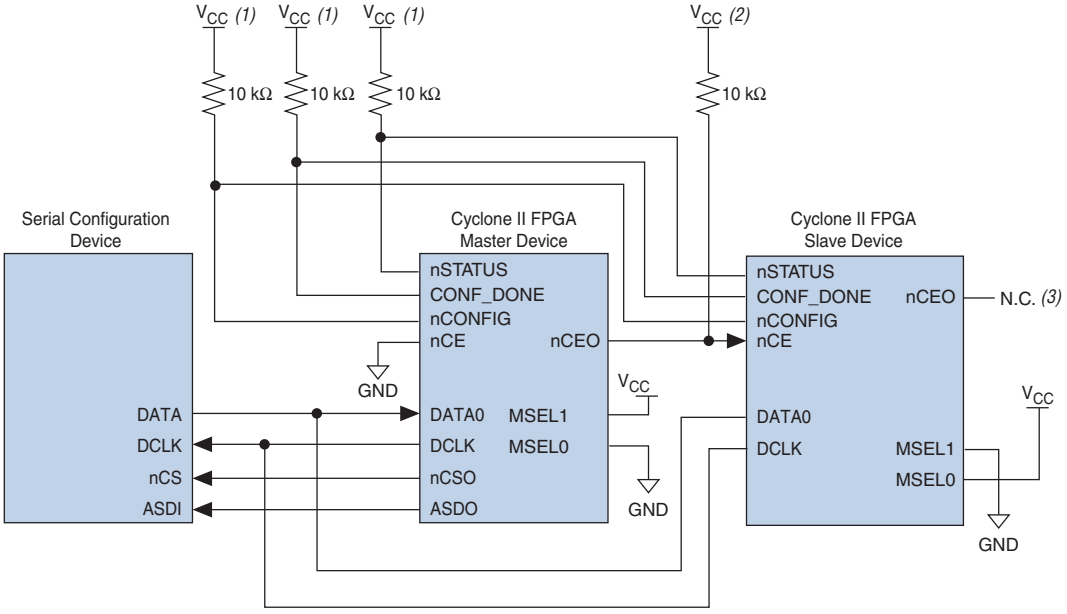
- Maintain equal distance between traces in LVDS pairs, as much as possible. Routing the pair of traces close to each other maximizes the common-mode rejection ratio (CMRR).
- Longer traces have more inductance and capacitance. These traces should be as short as possible to limit signal integrity issues.
- Place termination resistors as close to receiver input pins as possible.
- Use surface mount components.
- Avoid 90° or 45° corners.
- Use high-performance connectors.
- Design backplane and card traces so that trace impedance matches the connector's and/or the termination's impedance.
- Keep equal number of vias for both signal traces.
- Create equal trace lengths to avoid skew between signals. Unequal trace lengths result in misplaced crossing points and decrease system margins as the channel-to-channel skew (TCCS) value increases.
- Limit vias because they cause discontinuities.
- Use the common bypass capacitor values such as 0.001, 0.01, and 0.1 µF to decouple the high-speed PLL power and ground planes.
- Keep switching transistor-to-transistor logic (TTL) signals away from differential signals to avoid possible noise coupling.
- Do not route TTL clock signals to areas under or above the differential signals.
- Analyze system-level signals.

For PCB layout guidelines, see *AN 224: High-Speed Board Layout Guidelines*.

Conclusion

Cyclone II differential I/O capabilities enable you to keep pace with increasing design complexity. Support for I/O standards including LVDS, LVPECL, RSDS, mini-LVDS, differential SSTL and differential HSTL allows Cyclone II devices to fit into a wide variety of applications. Taking advantage of these I/O capabilities and Cyclone II pricing allows you to lower your design costs while remaining on the cutting edge of technology.

Figure 13–4. Multiple Device AS Configuration



Notes to Figure 13–4:

(1) Connect the pull-up resistors to a 3.3-V supply.

(2) Connect the pull-up resistor to the V_{CCIO} supply voltage of I/O bank that the nCEO pin resides in.

(3) The nCEO pin can be left unconnected or used as a user I/O pin when it does not feed another device's nCE pin.

As shown in Figure 13–4, the nSTATUS and CONF_DONE pins on all target FPGAs are connected together with external pull-up resistors. These pins are open-drain bidirectional pins on the FPGAs. When the first device asserts nCEO (after receiving all of its configuration data), it releases its CONF_DONE pin. However, the subsequent devices in the chain keep the CONF_DONE signal low until they receive their configuration data. When all the target FPGAs in the chain have received their configuration data and have released CONF_DONE, the pull-up resistor pulls this signal high, and all devices simultaneously enter initialization mode.

You should put a buffer before the DATA and DCLK output from the master Cyclone II device to avoid signal strength and signal integrity issues. The buffer should not significantly change the DATA-to-DCLK relationships or delay them with respect to other AS signals (ASDI and nCS). Also, the buffer should only drive the slave Cyclone II devices, so that the timing between the master Cyclone II device and serial configuration device is unaffected.

This configuration method supports both compressed and uncompressed SOFs. Therefore, if the configuration bitstream size exceeds the capacity of a serial configuration device, you can enable the compression feature in the SOF file used or you can select a larger serial configuration device.

Estimating AS Configuration Time

The AS configuration time is the time it takes to transfer data from the serial configuration device to the Cyclone II device. The Cyclone II DCLK output (generated from an internal oscillator) clocks this serial interface. As listed in Table 13–5, if you are using the 40-MHz oscillator, the DCLK minimum frequency is 20 MHz (50 ns). Therefore, the maximum configuration time estimate for an EP2C5 device (1,223,980 bits of uncompressed data) is:

RBF size × (maximum DCLK period / 1 bit per DCLK cycle) = estimated maximum configuration time

1,223,980 bits × (50 ns / 1 bit) = 61.2 ms

To estimate the typical configuration time, use the typical DCLK period listed in Table 13–5. With a typical DCLK period of 38.46 ns, the typical configuration time is 47.1 ms. Enabling compression reduces the amount of configuration data that is transmitted to the Cyclone II device, which also reduces configuration time. On average, compression reduces configuration time by 50%.

device releases its nSTATUS pin after a reset time-out period (maximum of 40 µs). When the nSTATUS pin is released and pulled high by a pull-up resistor, the configuration device reconfigures the chain. If this option is turned off, the external system must monitor nSTATUS for errors and then pulse nCONFIG low for at least 2 µs to restart configuration. The external system can pulse the nCONFIG pin if the pin is under system control rather than tied to V_{CC}.

Additionally, if the configuration device sends all of its data and then detects that the CONF_DONE pin has not transitioned high, it recognizes that the FPGA has not configured successfully. Enhanced configuration devices wait for 64 DCLK cycles after the last configuration bit was sent for the CONF_DONE pin to transition high. EPC2 devices wait for 16 DCLK cycles. After that, the configuration device pulls its OE pin low, which in turn drives the target device's nSTATUS pin low. If you turn on the **Auto-restart configuration after error** option in the Quartus II software, the target device resets and then releases its nSTATUS pin after a reset time-out period (maximum of 40 µs). When nSTATUS transitions high again, the configuration device reconfigures the FPGA.

For more information on configuration issues, see the *Debugging Configuration Problems* chapter of the *Configuration Handbook* and the FPGA Configuration Troubleshooter on the Altera web site (**www.altera.com**).

Multiple Device PS Configuration Using a Configuration Device

You can use Altera enhanced configuration devices (EPC16, EPC8, and EPC4 devices) or EPC2 and EPC1 configuration devices to configure multiple Cyclone II devices in a PS configuration chain.

Figure 13–14 shows how to configure multiple devices with an enhanced configuration device. This circuit is similar to the configuration device circuit for a single device, except Cyclone II devices are cascaded for multiple device configuration.

feature. To use this feature successfully, set the MSEL[1..0] pins of the master Cyclone II device to select the AS configuration scheme or fast AS configuration scheme (see Table 13–1).

The Quartus II software version 4.1 and higher supports serial configuration device ISP through an FPGA JTAG interface using a JIC file.

The serial configuration device in-system programming through the Cyclone II JTAG interface has three stages, which are described in the following sections.

Loading the Serial Flash Loader Design

The serial flash loader design is a design inside the Cyclone II device that bridges the JTAG interface and AS interface inside the Cyclone II device using glue logic.

The intelligent host uses the JTAG interface to configure the master Cyclone II device with a serial flash loader design. The serial flash loader design allows the master Cyclone II device to control the access of four serial configuration device pins, also known as the Active Serial Memory Interface (ASMI) pins, through the JTAG interface. The ASMI pins are the serial clock input (DCLK), serial data output (DATA), AS data input (ASDI), and an active-low chip select (nCS) pins.

If you configure a master Cyclone II device with a serial flash loader design, the master Cyclone II device can enter user mode even though the slave devices in the multiple device chain are not being configured. The master Cyclone II device can enter user mode with a serial flash loader design even though the CONF_DONE signal is externally held low by the other slave devices in chain. Figure 13–25 shows the JTAG configuration of a single Cyclone II device with a serial flash loader design.

Table 13–12 describes the optional configuration pins. If these optional configuration pins are not enabled in the Quartus II software, they are available as general-purpose user I/O pins. Therefore during configuration, these pins function as user I/O pins and are tri-stated with weak pull-up resistors.

Table 13–12. Optional Configuration Pins

Pin Name	User Mode	Pin Type	Description
CLKUSR	N/A if option is on. I/O if option is off.	Input	This is an optional user-supplied clock input that synchronizes the initialization of one or more devices. This pin is enabled by turning on the **Enable user-supplied start-up clock (CLKUSR)** option in the Quartus II software
INIT_DONE	N/A if option is on. I/O if option is off.	Output open-drain	This is a status pin that can be used to indicate when the device has initialized and is in user mode. When nCONFIG is low and during the beginning of configuration, the INIT_DONE pin is tri-stated and pulled high due to an external 10-kΩ pull-up resistor. Once the option bit to enable INIT_DONE is programmed into the device (during the first frame of configuration data), the INIT_DONE pin goes low. When initialization is complete, the INIT_DONE pin is released and pulled high and the FPGA enters user mode. Thus, the monitoring circuitry must be able to detect a low-to-high transition. This pin is enabled by turning on the **Enable INIT_DONE output** option in the Quartus II software.
DEV_OE	N/A if option is on. I/O if option is off.	Input	Optional pin that allows the user to override all tri-states on the device. When this pin is driven low, all I/O pins are tri-stated. When this pin is driven high, all I/O pins behave as programmed. This pin is enabled by turning on the **Enable device-wide output enable (DEV_OE)** option in the Quartus II software.
DEV_CLRn	N/A if option is on. I/O if option is off.	Input	Optional pin that allows you to override all clears on all device registers. When this pin is driven low, all registers are cleared. When this pin is driven high, all registers behave as programmed. This pin is enabled by turning on the **Enable device-wide reset (DEV_CLRn)** option in the Quartus II software.

Tables 15–5 and 15–6 show the package information and package outline figure references, respectively, for the 144-pin TQFP package.

Table 15–5. 144-Pin TQFP Package Information

Description	Specification
Ordering code reference	T
Package acronym	TQFP
Lead frame material	Copper
Lead finish (plating)	Regular: 85Sn:15Pb (Typ.) Pb-free: Matte Sn
JEDEC Outline Reference	MS-026 Variation: BFB
Maximum lead coplanarity	0.003 inches (0.08mm)
Weight	1.3 g
Moisture sensitivity level	Printed on moisture barrier bag

Table 15–6. 144-Pin TQFP Package Outline Dimensions

Symbol	Millimeter		
	Min.	Nom.	Max.
A	–	–	1.60
A1	0.05	–	0.15
A2	1.35	1.40	1.45
D	22.00 BSC		
D1	20.00 BSC		
E	22.00 BSC		
E1	20.00 BSC		
L	0.45	0.60	0.75
L1	1.00 REF		
S	0.20	–	–
b	0.17	0.22	0.27
c	0.09	–	0.20
e	0.50 BSC		
θ	0°	3.5°	7°